

Algemene informatie

Aanbesteding: Wafer Level Reliability Tool
Aanbestedende Dienst: Technische Universiteit Eindhoven
Referentie: PCM2026-10183RfP
Toelichting:
-

Vraag en antwoord

Ref.nr. 1	Onderwerp: O-O tests Vraag: Are optical in – optical out tests required ? And if so, are these tests with fiber arrays or single fibers ? Antwoord: Yes, optical in and out is a must. We will use mainly fiber arrays but will require ability to swap to single fiber if needed. Fase: Inschrijffase Inschrijfronde: Inschrijfronde 1 Vragenronde: Vragenronde 1 Beantwoord op: 9 okt 2026 Percelen: P1 Wafer Level Reliability Tool
Ref.nr. 2	Onderwerp: Multi-channel measurements Vraag: You refer to parallel multi channel SMU measurements : could you specify the required number of channels ? Antwoord: 16 at least, 4-wire measurement capability Fase: Inschrijffase Inschrijfronde: Inschrijfronde 1

Vragenronde:

Vragenronde 1

Beantwoord op:

9 okt 2026

Percelen:

P1 Wafer Level Reliability Tool

Ref.nr.

3

Onderwerp:

Instrumentation

Vraag:

Can you specify in more detail which types of instruments are required in the system ?

Antwoord:

A rough system concept would include a multi-channel low-current SMU system (approximately 16 channels) for device biasing and electrical characterization, an electrical switching matrix capable of routing to roughly 128 probe connections, an optical switching matrix with approximately 16 channels, an O-band tunable laser source, an optical power meter or multi-channel power measurement system, VOA, polarization controller, and a broadband optical source for alignment and passive spectral measurements.

Fase:

Inschrijffase

Inschrijfronde:

Inschrijfronde 1

Vragenronde:

Vragenronde 1

Beantwoord op:

9 okt 2026

Percelen:

P1 Wafer Level Reliability Tool

Ref.nr.

4

Onderwerp:

Mechanical resolution spec

Vraag:

Your minimal requirement states : "The system shall provide high-precision, repeatable stage and electrical probe movement ($\pm 0.25 \mu\text{m}$ bidirectional positional repeatability)" No one in the market can deliver this. Could you review this requirement ?

Antwoord:

This requirement has been changed as follows:

Bidirectional positional repeatability of the motorized electrical probe positioning axes shall be $\leq \pm 2 \mu\text{m}$ (or $\leq 4 \mu\text{m}$ peak-to-peak), Positional drift at the probe-to-sample interface shall not exceed $3 \mu\text{m}$ over an 8-hour measurement period.

The supplier shall specify, for the proposed configuration:

- positioning resolution;
- positioning accuracy;
- unidirectional and/or bidirectional repeatability;
- long-term positional drift/stability;
- the measurement conditions and methodology used to determine these specifications

Fase:

Inschrijffase

Inschrijfronde:

Inschrijfronde 1

Vragenronde:

Vragenronde 1

Beantwoord op:

9 okt 2026

Percelen:

P1 Wafer Level Reliability Tool